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|---|---|----|--------------------------|----------------------------------|--|
| Substitute for form 1449A/B/PTO   |   |    | <b>Complete if Known</b> |                                  |  |
|   |   |    | Application Number       | Not Yet Assigned <b>10579654</b> |  |
| <b>INFORMATION DISCLOSURE<br/>STATEMENT BY APPLICANT</b><br><br>(Use as many sheets as necessary) |   |    | Filing Date              | Concurrently Herewith            |  |
|   |   |    | First Named Inventor     | Paul Meredith                    |  |
|   |   |    | Art Unit                 | N/A                              |  |
|   |   |    | Examiner Name            | Not Yet Assigned                 |  |
|   |   |    | Attorney Docket Number   | 6106-000006/US/NP                |  |
| Sheet   | 1 | of | 1                        |                                  |  |

| U.S. PATENT DOCUMENTS |                       |   |                                |  |   |
|-----------------------|-----------------------|---|--------------------------------|--|---|
| Examiner Initials*    | Cite No. <sup>1</sup> | Document Number<br>Number-Kind Code <sup>2</sup> (if known) | Publication Date<br>MM-DD-YYYY | Name of Patentee or<br>Applicant of Cited Document | Pages, Columns, Lines, Where<br>Relevant Passages or Relevant<br>Figures Appear |
| /A.W./                | AA*                   | US-6,599,976-B1   | 07-29-2003                     | KOBAYASHI et al                                    |   |
| /A.W./                | AB*                   | US-6,403,183-B1   | 06-11-2002                     | IWAMIYA et al                                      |   |
| /A.W./                | AC*                   | US-6,291,697-B1   | 09-18-2001                     | TANAKA et al                                       |   |
| /A.W./                | AD*                   | US-6,099,911*   | 08-08-2000                     | YANO et al   |   |
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| FOREIGN PATENT DOCUMENTS |                       |   |  |                                |  |   |
|--------------------------|-----------------------|---|--|--------------------------------|--|---|
| Examiner Initials*       | Cite No. <sup>1</sup> | Foreign Patent Document   |  | Publication Date<br>MM-DD-YYYY | Name of Patentee or<br>Applicant of Cited Document | Pages, Columns, Lines,<br>Where Relevant Passages or<br>Relevant Figures Appear |
|                          |                       | Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known) |  |                                |  |   |
| /A.W./                   | BA                    | EP-834488-A*  |  | 04-08-1998                     |  | ✓   |
| /A.W./                   | BB                    | EP-1074859-A**  |  | 02-07-2001                     |  | ✓   |
| /A.W./                   | BC                    | JP-10-226767  |  | 08-25-1998                     |  | ✓   |
| /A.W./                   | BD                    | JP-10-316934  |  | 12-02-1998                     |  | ✓   |
| /A.W./                   | BE                    | JP-08-120225  |  | 05-14-1996                     |  | ✓   |
| /A.W./                   | BF                    | JP-04-180977  |  | 06-29-1992                     |  | ✓   |

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. \* CITE NO.: Those application(s) which are marked with an single asterisk (\*) next to the Cite No. are not supplied (under 37 CFR 1.98(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. <sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

\* EP-834488-A corresponds to US-6,099,911

\*\*EP-1074859-A corresponds to US-6,511,721

| NON PATENT LITERATURE DOCUMENTS |                       |   |                |
|---------------------------------|-----------------------|---|----------------|
| Examiner Initials*              | Cite No. <sup>1</sup> | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. | T <sup>2</sup> |
| /A.W./                          | CA                    | ISHINO et al., "Mass production of hydrophobic silica aerogel and readout optics of Cherenkov light", Nuclear Instruments and Methods in Physics Research A 457 (2001) pp 581-587.  |                |

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<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.

|                    |                    |                 |            |
|--------------------|--------------------|-----------------|------------|
| Examiner Signature | /Alexander Weddle/ | Date Considered | 08/18/2009 |
|--------------------|--------------------|-----------------|------------|

DAM/dl